

DATE Best Paper Awards

Each year the Design, Automation and Test in Europe Conference presents awards to the authors of the best papers. The selection is performed by an award committee, based on the results of the reviewing process, the quality of the final paper, and (until DATE 2012) the quality of the presentation.

The **DATE 2012** best paper is:

COMPOSITIONAL SYSTEM-LEVEL DESIGN EXPLORATION WITH PLANNING OF HIGH-LEVEL SYNTHESIS

Hung-Yi Liu, Michele Petracca, and Luca P. Carloni, Columbia University, US.

The **DATE 2013** best papers are:

D Track

AVICA: AN ACCESS-TIME VARIATION INSENSITIVE L1 CACHE ARCHITECTURE

Seokin Hong and Soontea Kim - Korea Advanced Institute of Science and Technology, KR

A Track

SCC THERMAL MODEL IDENTIFICATION VIA ADVANCED BIAS-COMPENSATED LEAST-SQUARES

Roberto Diversi, Andrea Bartolini, Andrea Tilli, Francesco Beneventi and Luca Benini - University of Bologna, IT

T Track:

HANDLING DISCONTINUOUS EFFECTS IN MODELING SPATIAL CORRELATION OF WAFER-LEVEL ANALOG/RF TESTS

Ke Huang and Yiorgos Makris - University of Texas at Dallas, US

and

Nathan Kupp - Yale University, US

and

John Carulli - Texas Instruments, US

E Track

FIFO CACHE ANALYSIS FOR WCET ESTIMATION: A QUANTITATIVE APPROACH

Nan Guan, Xinping Yang and Wang Yi - Uppsala University, SE

and

Mingsong Lv - Northeastern University, CN

Congratulations to the winners!